United States Design Patent

Nakano et al.

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INTEGRATED CIRCUIT TAG

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Field of Classification Search

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216/13; 361/718, 748, 752, 760, 783,
361/820; 428/901

See application file for complete search history.

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CLAIM

The ornamental design for an integrated circuit tag, as shown and described.

DESCRIPTION

FIG. 1 is a perspective view of an integrated circuit tag showing our new design;
FIG. 2 is a front elevational view thereof;
FIG. 3 is a right side elevational view thereof;
FIG. 4 is a left side elevational view thereof;
FIG. 5 is a top plan view thereof;
FIG. 6 is a bottom plan view thereof; and,
FIG. 7 is a cross sectional view thereof taken along the line 7-7 of FIG. 2.

The broken lines shown in the drawings represent portions of the integrated circuit tag that form no part of the claimed design. Dashed-dot-dashed broken lines define the boundaries of, but not included in, the claimed design.

1 Claim, 4 Drawing Sheets
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